

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 19.0009 Issue No.: 5 Status: Current

Supersedes: IECQ-L ULTW 19.0009 Issue 4 Issue Date: 2025/11/18 Org Issue: 2019/12/24

CB Reference No.: 50600264 ITL **Expiration: 2028/12/23**

ATP Electronics Taiwan Inc. Reliability Testing Laboratory

No. 16, Qiaoke 5th Rd., Yanchao Dist. Kaohsiung City 824005 Taiwan

The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

Reliability testing for memory and storage products.

See attached schedule.

-- Attached Schedule: IECQ-L_ULTW_50600264 ITL. Schedule 11-18-25.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road, Feng Yuan Dist., Taichung City Taiwan

Authorized person:

Bob CHEN







The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

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Appendix-1 (50600264 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Drop Test	ISTA 1,2A (ATP-03-10-0089)
High Temperature Operation Test	JESD22-A108 (ATP-03-10-0090)
High Temperature Storage Test	JESD22-A103 (ATP-03-10-0090)
Low Temperature Operation Test	JESD22-A108 (ATP-03-10-0095)
Low Temperature Storage Test	JESD22-A119 (ATP-03-10-0095)
Temperature and Humidity Test	IEC60068-2-78 (ATP-03-10-0099)
Temperature Cycling Test	JESD22-A104 (ATP-03-10-0098)

